

## 20V N-Channel Enhancement Mode MOSFET

### Description

The AP15N10S uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 20V$   $I_D = 15A$

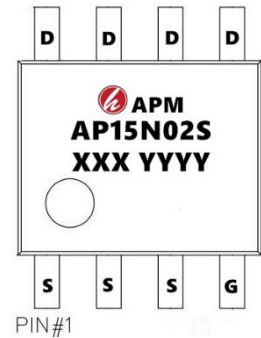
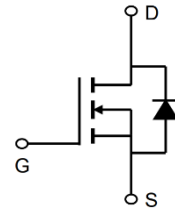
$R_{DS(ON)} < 8.0m\Omega$  @  $V_{GS}=4.5V$

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP15N02S	SOP-8	AP15N02S XXX YYYY	3000

### Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Max.	Units
$V_{DSS}$	Drain-Source Voltage	20	V
$V_{GSS}$	Gate-Source Voltage	±12	V
$I_D$	Continuous Drain Current $T_C = 25^\circ C$	15	A
$I_D$	Continuous Drain Current $T_C = 100^\circ C$	12	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>	45	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>	36	mJ
$P_D$	Power Dissipation $T_C = 25^\circ C$	31	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.84	°C/W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	°C



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### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

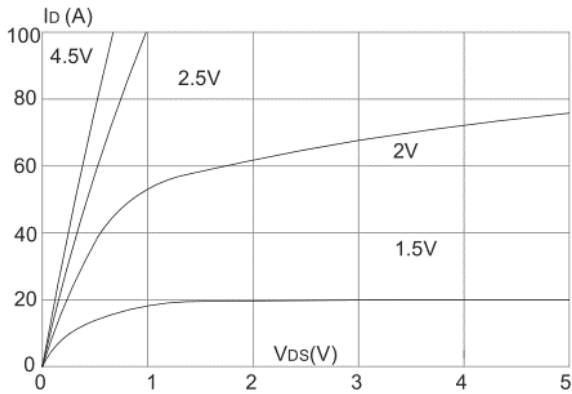
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20	22	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±12V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.4	0.7	1.1	V
RDS(on)	Static Drain-Source on-Resistance note3	V <sub>GS</sub> =4.5V, I <sub>D</sub> =25A	-	6.3	8.0	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =10A	-	8.8	13	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1.0MHz	-	1458	-	pF
C <sub>oss</sub>	Output Capacitance		-	238	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	212	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =10V, I <sub>D</sub> =25A, V <sub>GS</sub> =4.5V	-	19	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	3	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	6.4	-	nC
td(on)	Turn-on Delay Time	V <sub>DS</sub> =10V, I <sub>D</sub> =10A, R <sub>GEN</sub> =3Ω, V <sub>GS</sub> =4.5V	-	10	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	21	-	ns
td(off)	Turn-off Delay Time		-	39	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	19	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	50	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	200	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	IF=20A, dI/dt=100A/μs	-	25	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	20	-	nC

#### Notes:

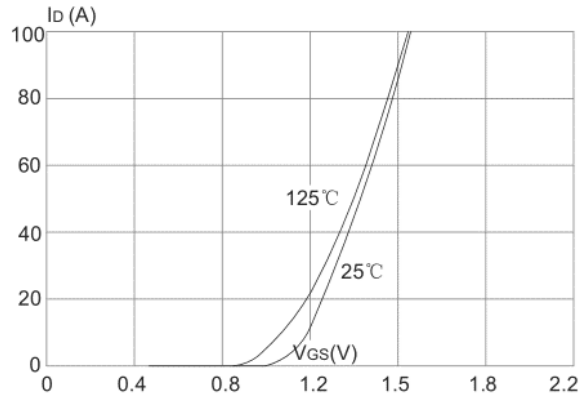
- 1、Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- 2、EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=10V, V<sub>G</sub>=4.5V, L=0.5mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=12A
- 3、Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

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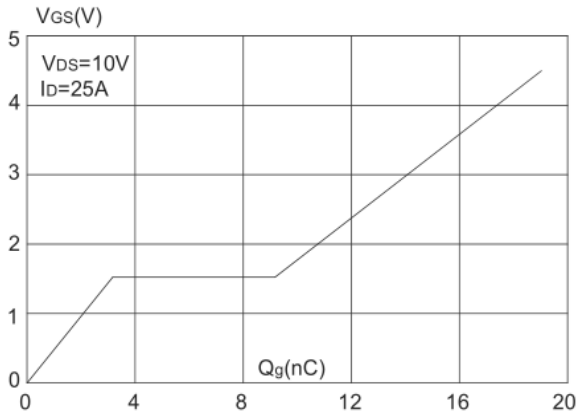
### Typical Characteristics



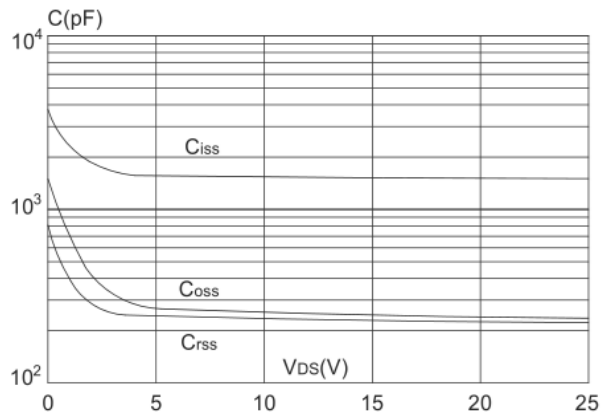
**Figure 1:** Output Characteristics



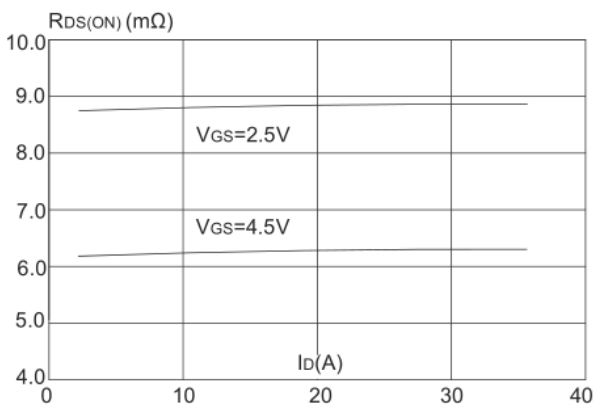
**Figure 2:** Typical Transfer Characteristics



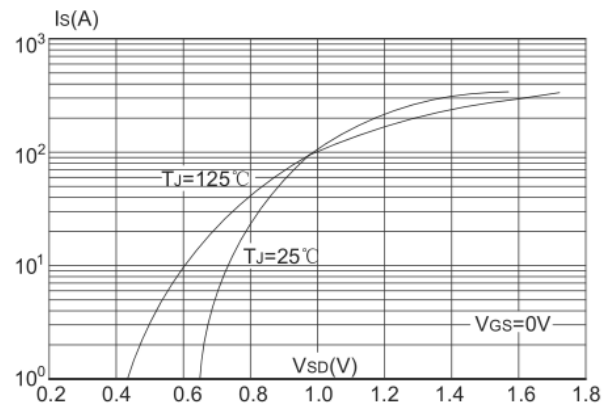
**Figure 3:** On-resistance vs. Drain Current



**Figure 4:** Body Diode Characteristics

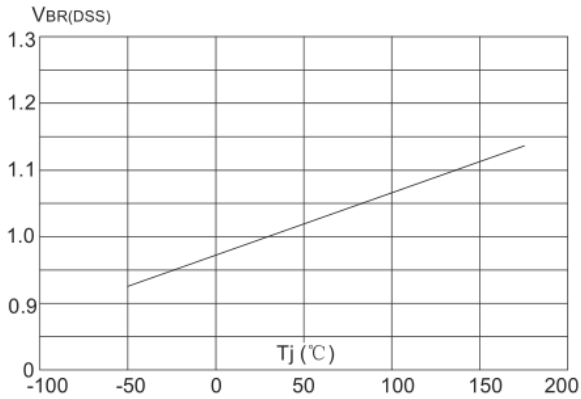


**Figure 5:** Gate Charge Characteristics

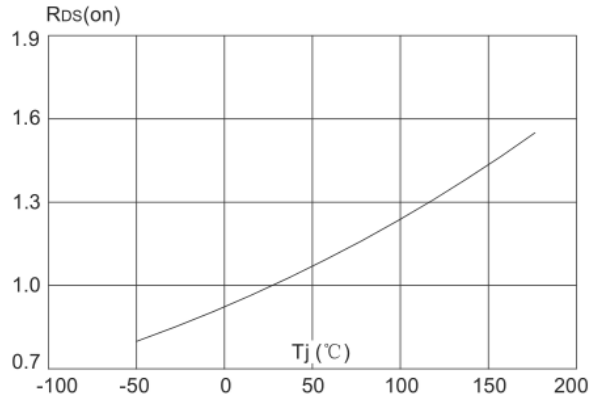


**Figure 6:** Capacitance Characteristics

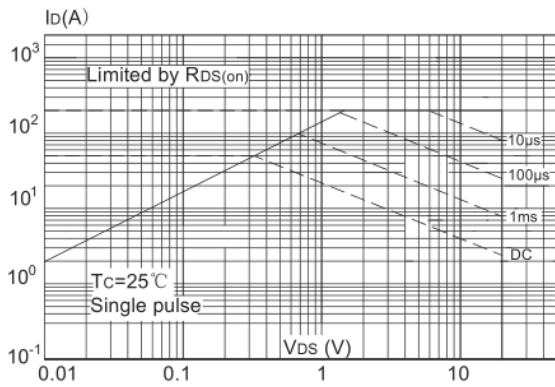
## 20V N-Channel Enhancement Mode MOSFET



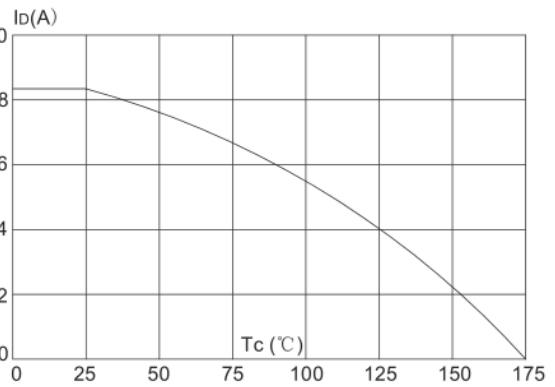
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



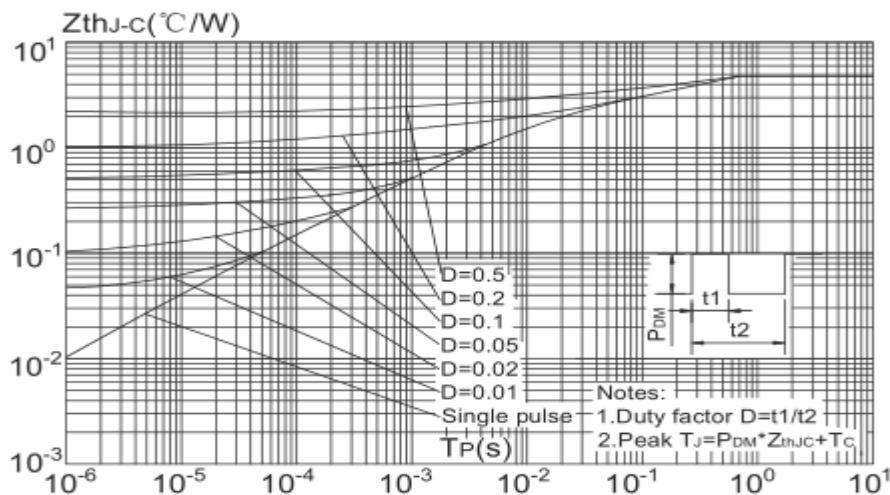
**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 9:** Maximum Safe Operating Area

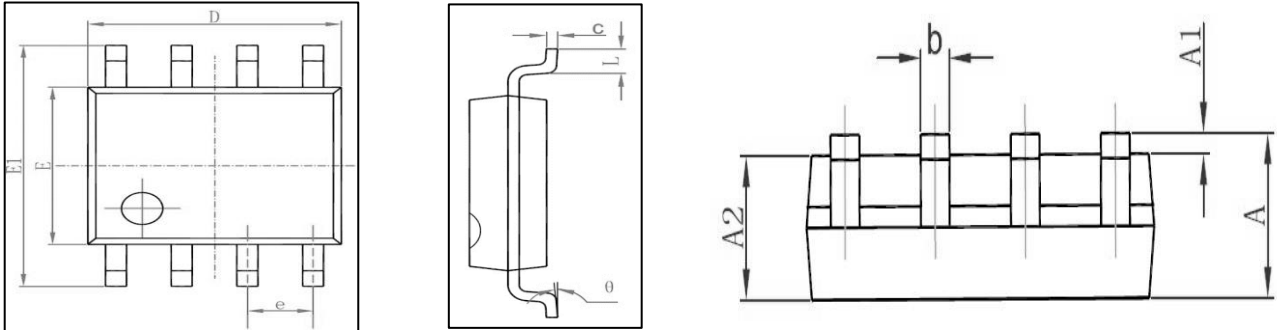


**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature

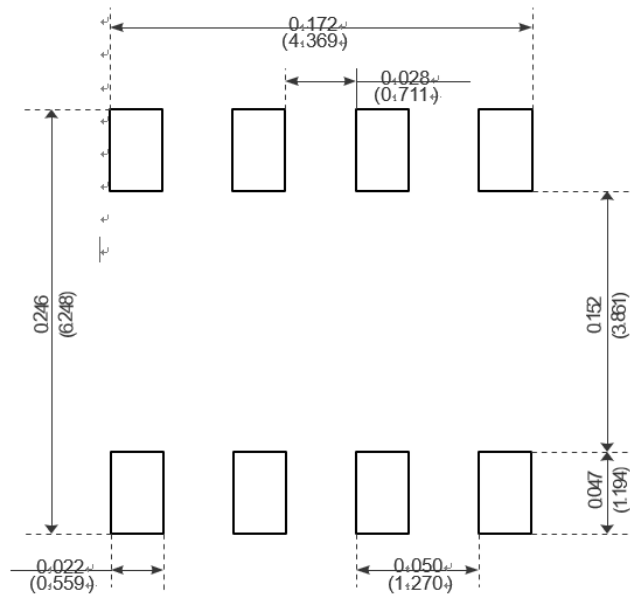


**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case

**Package Mechanical Data-SOP-8**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°



Recommended Minimum Pads

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Edition	Date	Change
Rve1.0	2020/9/11	Initial release

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